

Index to: Reliability Toolkit: Commercial Practices Edition

A Facilitator for Using the Rome Laboratory/RAC
"Reliability Toolkit: Commercial Practices Edition"

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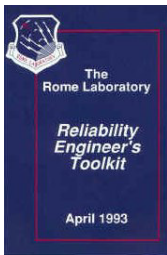
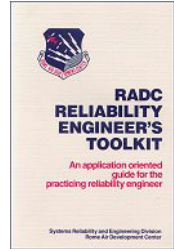


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Introduction

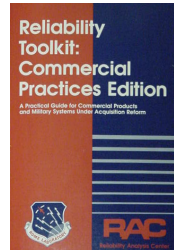
QUANTERION SOLUTIONS principals **Preston MacDiarmid** and **Seymour Morris** have been the leaders, and the primary authors, of the very popular “Toolkit” series of publications (more than 20,000 copies distributed). The following may clarify the somewhat confusing history of the series:

- **RADC Reliability Engineer’s Toolkit** - the first version (gray) developed by **Rome Air Development Center** (later renamed **Rome Laboratory**) was released in 1988 and was distributed primarily by RADC for free. MacDiarmid and Morris were both RADC staff members at the time.



- **Rome Laboratory Reliability Engineer’s Toolkit** - the second version (blue) was released by Rome Laboratory in 1993, but was distributed by the **Reliability Analysis Center (RAC)**. Morris was still at RL and MacDiarmid had moved to industry and had become Director of the RAC.

- **Reliability Toolkit: Commercial Practices Edition** - The third book (red/blue) in the series was developed jointly by Rome Laboratory and the RAC, with Morris at RL and MacDiarmid at the RAC. It represented a significant expansion of the content, particularly striving to address commercial practices, and the impact on military reliability and maintainability as a result of Defense Acquisition Reform.



- **Index to Reliability Toolkit: Commercial Practices Edition** - This FREE reference that you’re reading was developed by Quanterion to overcome a shortcoming in the third generation Toolkit. We hope that you will find it to be a valuable tool in more quickly accessing the Toolkit information that you need.

- **Q-Tools PRO** - **Quanterion’s Q-Tools PRO** represents the next logical step in the toolkit series dedicated to providing practical RMQ knowledge. It provides automated versions of many widely used procedures and methodologies in RMQ from the hardcopy Toolkit series as well as other sources. Like the earlier toolkits, it is intended to be used as a daily reference, but now on your computer desktop instead of on your bookshelf. Check it out at quanterion.com.

QUANTERION SOLUTIONS offers reliability and maintainability engineering consulting services, including training and software development, to government and industry. Founders Preston MacDiarmid, Seymour Morris and David Mahar started the company with a goal of providing high quality **QUANT**itative engineering services to be used as **critERION** for critical decision making, hence the name **QUANTERION**. All principals have had significant roles in the RMQ fields at the Department of Defense **Reliability Analysis Center (RAC)** and at the US Air Force’s **Rome Laboratory**. MacDiarmid served as Director of the RAC for 10 years after a 17-year career at Rome Laboratory leading the DoD’s largest R&D program in system reliability. Morris had DoD responsibility for reliability analysis methodology, including responsibility for **MIL-HDBK-217 “Reliability Prediction of Electronic Equipment”** for 10 years. Mahar had responsibility for all RAC software and databases, such as the **Automated Data Book CD-ROM** incorporating RAC’s widely used **Nonelectronic Parts Reliability Data (NPRD)**, **Failure Mode/Mechanism Distribution Data (FMD-97)** and **Electronic Parts Reliability Data (EPRD)**. He also developed RAC’s recently released reliability analysis software tool, **PRISM**.

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